# E·XFL

## Intel - EPM7128AETC100-5N Datasheet



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## Understanding <u>Embedded - CPLDs (Complex</u> <u>Programmable Logic Devices)</u>

Embedded - CPLDs, or Complex Programmable Logic Devices, are highly versatile digital logic devices used in electronic systems. These programmable components are designed to perform complex logical operations and can be customized for specific applications. Unlike fixedfunction ICs, CPLDs offer the flexibility to reprogram their configuration, making them an ideal choice for various embedded systems. They consist of a set of logic gates and programmable interconnects, allowing designers to implement complex logic circuits without needing custom hardware.

#### Applications of Embedded - CPLDs

## Details

Product Status	Obsolete
Programmable Type	In System Programmable
Delay Time tpd(1) Max	5 ns
Voltage Supply - Internal	3V ~ 3.6V
Number of Logic Elements/Blocks	8
Number of Macrocells	128
Number of Gates	2500
Number of I/O	84
Operating Temperature	0°C ~ 70°C (TA)
Mounting Type	Surface Mount
Package / Case	100-TQFP
Supplier Device Package	100-TQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/intel/epm7128aetc100-5n

Email: info@E-XFL.COM

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The MAX 7000A architecture supports 100% transistor-to-transistor logic (TTL) emulation and high-density integration of SSI, MSI, and LSI logic functions. It easily integrates multiple devices including PALs, GALs, and 22V10s devices. MAX 7000A devices are available in a wide range of packages, including PLCC, BGA, FineLine BGA, Ultra FineLine BGA, PQFP, and TQFP packages. See Table 3 and Table 4.

Table 3. MAX 700	OA Maximum U	lser I/O Pins	Note (1)			
Device	44-Pin PLCC	44-Pin TQFP	49-Pin Ultra FineLine BGA (2)	84-Pin PLCC	100-Pin TQFP	100-Pin FineLine BGA (3)
EPM7032AE	36	36				
EPM7064AE	36	36	41		68	68
EPM7128A				68	84	84
EPM7128AE				68	84	84
EPM7256A					84	
EPM7256AE					84	84
EPM7512AE						

Table 4. MAX 7000A Maximum User I/O Pins     Note (1)								
Device	144-Pin TQFP	169-Pin Ultra FineLine BGA <i>(2)</i>	208-Pin PQFP	256-Pin BGA	256-Pin FineLine BGA (3)			
EPM7032AE								
EPM7064AE								
EPM7128A	100				100			
EPM7128AE	100	100			100			
EPM7256A	120		164		164			
EPM7256AE	120		164		164			
EPM7512AE	120		176	212	212			

#### Notes to tables:

- (1) When the IEEE Std. 1149.1 (JTAG) interface is used for in-system programming or boundary-scan testing, four I/O pins become JTAG pins.
- (2) All Ultra FineLine BGA packages are footprint-compatible via the SameFrame<sup>TM</sup> feature. Therefore, designers can design a board to support a variety of devices, providing a flexible migration path across densities and pin counts. Device migration is fully supported by Altera development tools. See "SameFrame Pin-Outs" on page 15 for more details.
- (3) All FineLine BGA packages are footprint-compatible via the SameFrame feature. Therefore, designers can design a board to support a variety of devices, providing a flexible migration path across densities and pin counts. Device migration is fully supported by Altera development tools. See "SameFrame Pin-Outs" on page 15 for more details.

MAX 7000A devices use CMOS EEPROM cells to implement logic functions. The user-configurable MAX 7000A architecture accommodates a variety of independent combinatorial and sequential logic functions. The devices can be reprogrammed for quick and efficient iterations during design development and debug cycles, and can be programmed and erased up to 100 times.

MAX 7000A devices contain from 32 to 512 macrocells that are combined into groups of 16 macrocells, called logic array blocks (LABs). Each macrocell has a programmable-AND/fixed-OR array and a configurable register with independently programmable clock, clock enable, clear, and preset functions. To build complex logic functions, each macrocell can be supplemented with both shareable expander product terms and highspeed parallel expander product terms, providing up to 32 product terms per macrocell.

MAX 7000A devices provide programmable speed/power optimization. Speed-critical portions of a design can run at high speed/full power, while the remaining portions run at reduced speed/low power. This speed/power optimization feature enables the designer to configure one or more macrocells to operate at 50% or lower power while adding only a nominal timing delay. MAX 7000A devices also provide an option that reduces the slew rate of the output buffers, minimizing noise transients when non-speed-critical signals are switching. The output drivers of all MAX 7000A devices can be set for 2.5 V or 3.3 V, and all input pins are 2.5-V, 3.3-V, and 5.0-V tolerant, allowing MAX 7000A devices to be used in mixed-voltage systems.

MAX 7000A devices are supported by Altera development systems, which are integrated packages that offer schematic, text—including VHDL, Verilog HDL, and the Altera Hardware Description Language (AHDL)—and waveform design entry, compilation and logic synthesis, simulation and timing analysis, and device programming. The software provides EDIF 2 0 0 and 3 0 0, LPM, VHDL, Verilog HDL, and other interfaces for additional design entry and simulation support from other industry-standard PC- and UNIX-workstation-based EDA tools. The software runs on Windows-based PCs, as well as Sun SPARCstation, and HP 9000 Series 700/800 workstations.

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For more information on development tools, see the *MAX+PLUS II Programmable Logic Development System & Software Data Sheet* and the *Quartus Programmable Logic Development System & Software Data Sheet*.

# SameFrame Pin-Outs

MAX 7000A devices support the SameFrame pin-out feature for FineLine BGA packages. The SameFrame pin-out feature is the arrangement of balls on FineLine BGA packages such that the lower-ballcount packages form a subset of the higher-ball-count packages. SameFrame pin-outs provide the flexibility to migrate not only from device to device within the same package, but also from one package to another. A given printed circuit board (PCB) layout can support multiple device density/package combinations. For example, a single board layout can support a range of devices from an EPM7128AE device in a 100-pin FineLine BGA package to an EPM7512AE device in a 256-pin FineLine BGA package.

The Altera design software provides support to design PCBs with SameFrame pin-out devices. Devices can be defined for present and future use. The software generates pin-outs describing how to lay out a board to take advantage of this migration (see Figure 7).





Printed Circuit Board Designed for 256-Pin FineLine BGA Package



 

 100-Pin FineLine BGA Package (Reduced I/O Count or Logic Requirements)
 256-Pin FineLine BGA Package (Increased I/O Count or Logic Requirements)

# In-System Programmability

MAX 7000A devices can be programmed in-system via an industrystandard 4-pin IEEE Std. 1149.1 (JTAG) interface. ISP offers quick, efficient iterations during design development and debugging cycles. The MAX 7000A architecture internally generates the high programming voltages required to program EEPROM cells, allowing in-system programming with only a single 3.3-V power supply. During in-system programming, the I/O pins are tri-stated and weakly pulled-up to eliminate board conflicts. The pull-up value is nominally 50 k $\Omega$ .

MAX 7000AE devices have an enhanced ISP algorithm for faster programming. These devices also offer an ISP\_Done bit that provides safe operation when in-system programming is interrupted. This ISP\_Done bit, which is the last bit programmed, prevents all I/O pins from driving until the bit is programmed. This feature is only available in EPM7032AE, EPM7064AE, EPM7128AE, EPM7256AE, and EPM7512AE devices.

ISP simplifies the manufacturing flow by allowing devices to be mounted on a PCB with standard pick-and-place equipment before they are programmed. MAX 7000A devices can be programmed by downloading the information via in-circuit testers, embedded processors, the Altera MasterBlaster serial/USB communications cable, ByteBlasterMV parallel port download cable, and BitBlaster serial download cable. Programming the devices after they are placed on the board eliminates lead damage on high-pin-count packages (e.g., QFP packages) due to device handling. MAX 7000A devices can be reprogrammed after a system has already shipped to the field. For example, product upgrades can be performed in the field via software or modem.

In-system programming can be accomplished with either an adaptive or constant algorithm. An adaptive algorithm reads information from the unit and adapts subsequent programming steps to achieve the fastest possible programming time for that unit. A constant algorithm uses a predefined (non-adaptive) programming sequence that does not take advantage of adaptive algorithm programming time improvements. Some in-circuit testers cannot program using an adaptive algorithm. Therefore, a constant algorithm must be used. MAX 7000AE devices can be programmed with either an adaptive or constant (non-adaptive) algorithm. EPM7128A and EPM7256A device can only be programmed with an adaptive algorithm; users programming these two devices on platforms that cannot use an adaptive algorithm should use EPM7128AE and EPM7256AE devices.

The Jam Standard Test and Programming Language (STAPL), JEDEC standard JESD 71, can be used to program MAX 7000A devices with incircuit testers, PCs, or embedded processors.

TADIE 6. MAX TUUUA							
JTAG Instruction	Description						
SAMPLE/PRELOAD	Allows a snapshot of signals at the device pins to be captured and examined during normal device operation, and permits an initial data pattern output at the device pins						
EXTEST	Allows the external circuitry and board-level interconnections to be tested by forcing a test pattern at the output pins and capturing test results at the input pins						
BYPASS	Places the 1-bit bypass register between the TDI and TDO pins, which allows the BST data to pass synchronously through a selected device to adjacent devices during normal device operation						
IDCODE	Selects the IDCODE register and places it between the TDI and TDO pins, allowing the IDCODE to be serially shifted out of TDO						
USERCODE	Selects the 32-bit USERCODE register and places it between the TDI and TDO pins, allowing the USERCODE value to be shifted out of TDO. The USERCODE instruction is available for MAX 7000AE devices only						
UESCODE	These instructions select the user electronic signature (UESCODE) and allow the UESCODE to be shifted out of TDO. UESCODE instructions are available for EPM7128A and EPM7256A devices only.						
ISP Instructions	These instructions are used when programming MAX 7000A devices via the JTAG ports with the MasterBlaster, ByteBlasterMV, or BitBlaster download cable, or using a Jam STAPL File, JBC File, or SVF File via an embedded processor or test equipment.						

# Table 8. MAX 7000A JTAG Instructions

# Programmable Speed/Power Control

MAX 7000A devices offer a power-saving mode that supports low-power operation across user-defined signal paths or the entire device. This feature allows total power dissipation to be reduced by 50% or more because most logic applications require only a small fraction of all gates to operate at maximum frequency.

The designer can program each individual macrocell in a MAX 7000A device for either high-speed (i.e., with the Turbo Bit<sup>TM</sup> option turned on) or low-power operation (i.e., with the Turbo Bit option turned off). As a result, speed-critical paths in the design can run at high speed, while the remaining paths can operate at reduced power. Macrocells that run at low power incur a nominal timing delay adder ( $t_{LPA}$ ) for the  $t_{LAD}$ ,  $t_{LAC}$ ,  $t_{IC}$ ,  $t_{EN}$ ,  $t_{SEXP}$ ,  $\mathbf{t}_{ACL}$ , and  $\mathbf{t_{CPPW}}$  parameters.

# Output Configuration

MAX 7000A device outputs can be programmed to meet a variety of system-level requirements.

# MultiVolt I/O Interface

The MAX 7000A device architecture supports the MultiVolt I/O interface feature, which allows MAX 7000A devices to connect to systems with differing supply voltages. MAX 7000A devices in all packages can be set for 2.5-V, 3.3-V, or 5.0-V I/O pin operation. These devices have one set of VCC pins for internal operation and input buffers (VCCINT), and another set for I/O output drivers (VCCIO).

The VCCIO pins can be connected to either a 3.3-V or 2.5-V power supply, depending on the output requirements. When the VCCIO pins are connected to a 2.5-V power supply, the output levels are compatible with 2.5-V systems. When the VCCIO pins are connected to a 3.3-V power supply, the output high is at 3.3 V and is therefore compatible with 3.3-V or 5.0-V systems. Devices operating with V<sub>CCIO</sub> levels lower than 3.0 V incur a slightly greater timing delay of  $t_{OD2}$  instead of  $t_{OD1}$ . Inputs can always be driven by 2.5-V, 3.3-V, or 5.0-V signals.

Table 12 describes the MAX 7000A MultiVolt I/O support.

Table 12. MAX 7000A MultiVolt I/O Support								
V <sub>CCIO</sub> Voltage Input Signal (V) Output Signal (V)								
	2.5 3.3 5.0 2.5 3.3 5.0							
2.5	~	~	~	$\checkmark$				
3.3	$\checkmark$	$\checkmark$	$\checkmark$		$\checkmark$	$\checkmark$		

## **Open-Drain Output Option**

MAX 7000A devices provide an optional open-drain (equivalent to open-collector) output for each I/O pin. This open-drain output enables the device to provide system-level control signals (e.g., interrupt and write enable signals) that can be asserted by any of several devices. This output can also provide an additional wired-OR plane.

Open-drain output pins on MAX 7000A devices (with a pull-up resistor to the 5.0-V supply) can drive 5.0-V CMOS input pins that require a high  $V_{IH}$ . When the open-drain pin is active, it will drive low. When the pin is inactive, the resistor will pull up the trace to 5.0 V to meet CMOS  $V_{OH}$  requirements. The open-drain pin will only drive low or tri-state; it will never drive high. The rise time is dependent on the value of the pull-up resistor and load impedance. The  $I_{OL}$  current specification should be considered when selecting a pull-up resistor.

## **Programmable Ground Pins**

Each unused I/O pin on MAX 7000A devices may be used as an additional ground pin. In EPM7128A and EPM7256A devices, utilizing unused I/O pins as additional ground pins requires using the associated macrocell. In MAX 7000AE devices, this programmable ground feature does not require the use of the associated macrocell; therefore, the buried macrocell is still available for user logic.

## **Slew-Rate Control**

The output buffer for each MAX 7000A I/O pin has an adjustable output slew rate that can be configured for low-noise or high-speed performance. A faster slew rate provides high-speed transitions for high-performance systems. However, these fast transitions may introduce noise transients into the system. A slow slew rate reduces system noise, but adds a nominal delay of 4 to 5 ns. When the configuration cell is turned off, the slew rate is set for low-noise performance. Each I/O pin has an individual EEPROM bit that controls the slew rate, allowing designers to specify the slew rate on a pin-by-pin basis. The slew rate control affects both the rising and falling edges of the output signal.

VCC

To Test

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capacitance)

#### Figure 9. MAX 7000A AC Test Conditions

Power supply transients can affect AC measurements. Simultaneous transitions of multiple outputs should be avoided for accurate measurement. Threshold tests 703 Ω [521 Ω] *≶* must not be performed under AC conditions. Large-amplitude, fast-ground-Device Output current transients normally occur as the device outputs discharge the load capacitances. When these transients flow through the parasitic inductance between 586 Ω [481 Ω] *≥* the device ground pin and the test system ground, significant reductions in Device input observable noise immunity can result. rise and fall Numbers in brackets are for 2.5-V times < 2 ns outputs. Numbers without brackets are for 3.3-V outputs.

# Operating Conditions

Tables 13 through 16 provide information on absolute maximum ratings, recommended operating conditions, operating conditions, and capacitance for MAX 7000A devices.

Table 13. MAX 7000A Device Absolute Maximum Ratings       Note (1)									
Symbol	Parameter	Conditions	Min	Max	Unit				
V <sub>CC</sub>	Supply voltage	With respect to ground (2)	-0.5	4.6	V				
VI	DC input voltage		-2.0	5.75	V				
I <sub>OUT</sub>	DC output current, per pin		-25	25	mA				
T <sub>STG</sub>	Storage temperature	No bias	-65	150	°C				
T <sub>A</sub>	Ambient temperature	Under bias	-65	135	°C				
TJ	Junction temperature	BGA, FineLine BGA, PQFP, and TQFP packages, under bias		135	°C				

#### MAX 7000A Programmable Logic Device Data Sheet

#### Notes to tables:

- (1) See the Operating Requirements for Altera Devices Data Sheet.
- (2) Minimum DC input voltage is -0.5 V. During transitions, the inputs may undershoot to -2.0 V for input currents less than 100 mA and periods shorter than 20 ns.
- (3) For EPM7128A and EPM7256A devices only, V<sub>CC</sub> must rise monotonically.
- (4) In MAX 7000AE devices, all pins, including dedicated inputs, I/O pins, and JTAG pins, may be driven before V<sub>CCINT</sub> and V<sub>CCIO</sub> are powered.
- (5) These devices support in-system programming for -40° to 100° C. For in-system programming support between -40° and 0° C, contact Altera Applications.
- (6) These values are specified under the recommended operating conditions shown in Table 14 on page 28.
- (7) The parameter is measured with 50% of the outputs each sourcing the specified current. The I<sub>OH</sub> parameter refers to high-level TTL or CMOS output current.
- (8) The parameter is measured with 50% of the outputs each sinking the specified current. The I<sub>OL</sub> parameter refers to low-level TTL or CMOS output current.
- (9) This value is specified for normal device operation. For MAX 7000AE devices, the maximum leakage current during power-up is  $\pm 300 \ \mu$ A. For EPM7128A and EPM7256A devices, leakage current during power-up is not specified.
- (10) For EPM7128A and EPM7256A devices, this pull-up exists while a device is programmed in-system.
- (11) For MAX 7000AE devices, this pull-up exists while devices are programmed in-system and in unprogrammed devices during power-up.
- (12) Capacitance is measured at 25 °C and is sample-tested only. The OE1 pin (high-voltage pin during programming) has a maximum capacitance of 20 pF.
- (13) The POR time for MAX 7000AE devices (except MAX 7128A and MAX 7256A devices) does not exceed 100 μs. The sufficient V<sub>CCINT</sub> voltage level for POR is 3.0 V. The device is fully initialized within the POR time after V<sub>CCINT</sub> reaches the sufficient POR voltage level.

Figure 10 shows the typical output drive characteristics of MAX 7000A devices.





# **Timing Model**

MAX 7000A device timing can be analyzed with the Altera software, a variety of popular industry-standard EDA simulators and timing analyzers, or with the timing model shown in Figure 11. MAX 7000A devices have predictable internal delays that enable the designer to determine the worst-case timing of any design. The software provides timing simulation, point-to-point delay prediction, and detailed timing analysis for device-wide performance evaluation.

Figure 11. MAX 7000A Timing Model



The timing characteristics of any signal path can be derived from the timing model and parameters of a particular device. External timing parameters, which represent pin-to-pin timing delays, can be calculated as the sum of internal parameters. Figure 12 shows the timing relationship between internal and external delay parameters.



See *Application Note 94 (Understanding MAX 7000 Timing)* for more information.

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Table 22. EPM7128AE Internal Timing Parameters (Part 2 of 2)       Note (1)									
Symbol	Parameter	Conditions	Speed Grade Unit						
			-5 -7 -10					10	
			Min	Max	Min	Max	Min	Max	
t <sub>EN</sub>	Register enable time			0.7		1.0		1.3	ns
t <sub>GLOB</sub>	Global control delay			1.1		1.6		2.0	ns
t <sub>PRE</sub>	Register preset time			1.4		2.0		2.7	ns
t <sub>CLR</sub>	Register clear time			1.4		2.0		2.7	ns
t <sub>PIA</sub>	PIA delay	(2)		1.4		2.0		2.6	ns
t <sub>LPA</sub>	Low-power adder	(6)		4.0		4.0		5.0	ns

Table 23. EPM7256AE External Timing Parameters       Note (1)									
Symbol	Parameter	Conditions			Speed	Grade			Unit
			-;	5	-	7	-1	0	_
			Min	Max	Min	Max	Min	Max	
t <sub>PD1</sub>	Input to non- registered output	C1 = 35 pF (2)		5.5		7.5		10	ns
t <sub>PD2</sub>	I/O input to non- registered output	C1 = 35 pF (2)		5.5		7.5		10	ns
t <sub>SU</sub>	Global clock setup time	(2)	3.9		5.2		6.9		ns
t <sub>H</sub>	Global clock hold time	(2)	0.0		0.0		0.0		ns
t <sub>FSU</sub>	Global clock setup time of fast input		2.5		3.0		3.0		ns
t <sub>FH</sub>	Global clock hold time of fast input		0.0		0.0		0.0		ns
t <sub>CO1</sub>	Global clock to output delay	C1 = 35 pF	1.0	3.5	1.0	4.8	1.0	6.4	ns
t <sub>CH</sub>	Global clock high time		2.0		3.0		4.0		ns
t <sub>CL</sub>	Global clock low time		2.0		3.0		4.0		ns
t <sub>ASU</sub>	Array clock setup time	(2)	2.0		2.7		3.6		ns
t <sub>AH</sub>	Array clock hold time	(2)	0.2		0.3		0.5		ns
t <sub>ACO1</sub>	Array clock to output delay	C1 = 35 pF (2)	1.0	5.4	1.0	7.3	1.0	9.7	ns
t <sub>ACH</sub>	Array clock high time		2.0		3.0		4.0		ns
t <sub>ACL</sub>	Array clock low time		2.0		3.0		4.0		ns
t <sub>CPPW</sub>	Minimum pulse width for clear and preset	(3)	2.0		3.0		4.0		ns
t <sub>CNT</sub>	Minimum global clock period	(2)		5.8		7.9		10.5	ns
f <sub>CNT</sub>	Maximum internal global clock frequency	(2), (4)	172.4		126.6		95.2		MHz
t <sub>acnt</sub>	Minimum array clock period	(2)		5.8		7.9		10.5	ns
f <sub>acnt</sub>	Maximum internal array clock frequency	(2), (4)	172.4		126.6		95.2		MHz

Table 25	Table 25. EPM7512AE External Timing Parameters     Note (1)									
Symbol	Parameter	Conditions		Speed Grade Uni						
			-	7	-	10	-1	2		
			Min	Max	Min	Max	Min	Max		
t <sub>PD1</sub>	Input to non- registered output	C1 = 35 pF (2)		7.5		10.0		12.0	ns	
t <sub>PD2</sub>	I/O input to non- registered output	C1 = 35 pF <i>(</i> 2 <i>)</i>		7.5		10.0		12.0	ns	
t <sub>SU</sub>	Global clock setup time	(2)	5.6		7.6		9.1		ns	
t <sub>H</sub>	Global clock hold time	(2)	0.0		0.0		0.0		ns	
t <sub>FSU</sub>	Global clock setup time of fast input		3.0		3.0		3.0		ns	
t <sub>FH</sub>	Global clock hold time of fast input		0.0		0.0		0.0		ns	
t <sub>CO1</sub>	Global clock to output delay	C1 = 35 pF	1.0	4.7	1.0	6.3	1.0	7.5	ns	
t <sub>CH</sub>	Global clock high time		3.0		4.0		5.0		ns	
t <sub>CL</sub>	Global clock low time		3.0		4.0		5.0		ns	
t <sub>ASU</sub>	Array clock setup time	(2)	2.5		3.5		4.1		ns	
t <sub>AH</sub>	Array clock hold time	(2)	0.2		0.3		0.4		ns	
t <sub>ACO1</sub>	Array clock to output delay	C1 = 35 pF (2)	1.0	7.8	1.0	10.4	1.0	12.5	ns	
t <sub>ACH</sub>	Array clock high time		3.0		4.0		5.0		ns	
t <sub>ACL</sub>	Array clock low time		3.0		4.0		5.0		ns	
t <sub>CPPW</sub>	Minimum pulse width for clear and preset	(3)	3.0		4.0		5.0		ns	
t <sub>CNT</sub>	Minimum global clock period	(2)		8.6		11.5		13.9	ns	
f <sub>CNT</sub>	Maximum internal global clock frequency	(2), (4)	116.3		87.0		71.9		MHz	
t <sub>acnt</sub>	Minimum array clock period	(2)		8.6		11.5		13.9	ns	
facnt	Maximum internal array clock frequency	(2), (4)	116.3		87.0		71.9		MHz	

Table 28. EPM7128A Internal Timing Parameters (Part 2 of 2)       Note (1)											
Symbol	Parameter	Conditions	Speed Grade Unit								Unit
			-	6	-	7	-10		-12		
			Min	Мах	Min	Мах	Min	Max	Min	Мах	
t <sub>RD</sub>	Register delay			1.7		2.1		2.8		3.3	ns
t <sub>COMB</sub>	Combinatorial delay			1.7		2.1		2.8		3.3	ns
t <sub>IC</sub>	Array clock delay			2.4		3.0		4.1		4.9	ns
t <sub>EN</sub>	Register enable time			2.4		3.0		4.1		4.9	ns
t <sub>GLOB</sub>	Global control delay			1.0		1.2		1.7		2.0	ns
t <sub>PRE</sub>	Register preset time			3.1		3.9		5.2		6.2	ns
t <sub>CLR</sub>	Register clear time			3.1		3.9		5.2		6.2	ns
t <sub>PIA</sub>	PIA delay	(2)		0.9		1.1		1.5		1.8	ns
t <sub>LPA</sub>	Low-power adder	(6)		11.0		10.0		10.0		10.0	ns

The parameters in this equation are:

MC <sub>TON</sub>	=	Number of macrocells with the Turbo Bit option turned
		on, as reported in the MAX+PLUS II Report File (.rpt)
MC <sub>DEV</sub>	=	Number of macrocells in the device
MC <sub>USED</sub>	=	Total number of macrocells in the design, as reported in
		the Report File
f <sub>MAX</sub>	=	Highest clock frequency to the device
togLC	=	Average percentage of logic cells toggling at each clock
-20		(typically 12.5%)
A, B, C	=	Constants, shown in Table 31

Table 31. MAX 7000A I <sub>CC</sub> Equation Constants								
Device	A	В	C					
EPM7032AE	0.71	0.30	0.014					
EPM7064AE	0.71	0.30	0.014					
EPM7128A	0.71	0.30	0.014					
EPM7128AE	0.71	0.30	0.014					
EPM7256A	0.71	0.30	0.014					
EPM7256AE	0.71	0.30	0.014					
EPM7512AE	0.71	0.30	0.014					

This calculation provides an  $I_{CC}$  estimate based on typical conditions using a pattern of a 16-bit, loadable, enabled, up/down counter in each LAB with no output load. Actual  $I_{CC}$  should be verified during operation because this measurement is sensitive to the actual pattern in the device and the environmental operating conditions.



## Figure 13. I<sub>CC</sub> vs. Frequency for MAX 7000A Devices (Part 2 of 2)

# Device Pin-Outs

See the Altera web site (http://www.altera.com) or the *Altera Digital Library* for pin-out information.

Figures 14 through 23 show the package pin-out diagrams for MAX 7000A devices.

## Figure 14. 44-Pin PLCC/TQFP Package Pin-Out Diagram

Package outlines not drawn to scale.



Altera Corporation

#### Figure 19. 144-Pin TQFP Package Pin-Out Diagram

Package outline not drawn to scale.



Figure 20. 169-Pin Ultra FineLine BGA Package Pin-Out Diagram

Package outline not drawn to scale.



## Figure 21. 208-Pin PQFP Package Pin-Out Diagram

Package outline not drawn to scale.



### Figure 22. 256-Pin BGA Package Pin-Out Diagram

Package outline not drawn to scale.

